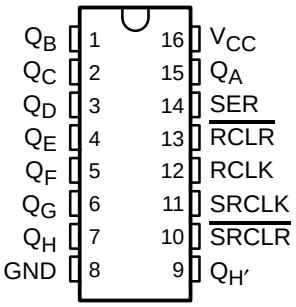
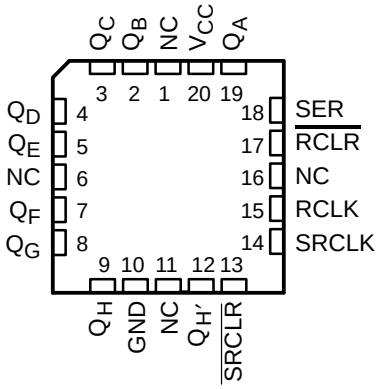
- **8-Bit Serial-In, Parallel-Out Shift Registers With Storage**
- **Independent Direct Overriding Clears on Shift and Storage Registers**
- **Independent Clocks for Both Shift and Storage Registers**
- **High-Current Outputs Can Drive up to 15 LSTTL Loads**
- **Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs**

SN54HC594 . . . J OR W PACKAGE
SN74HC594 . . . D OR N PACKAGE
(TOP VIEW)



SN54HC594 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

description

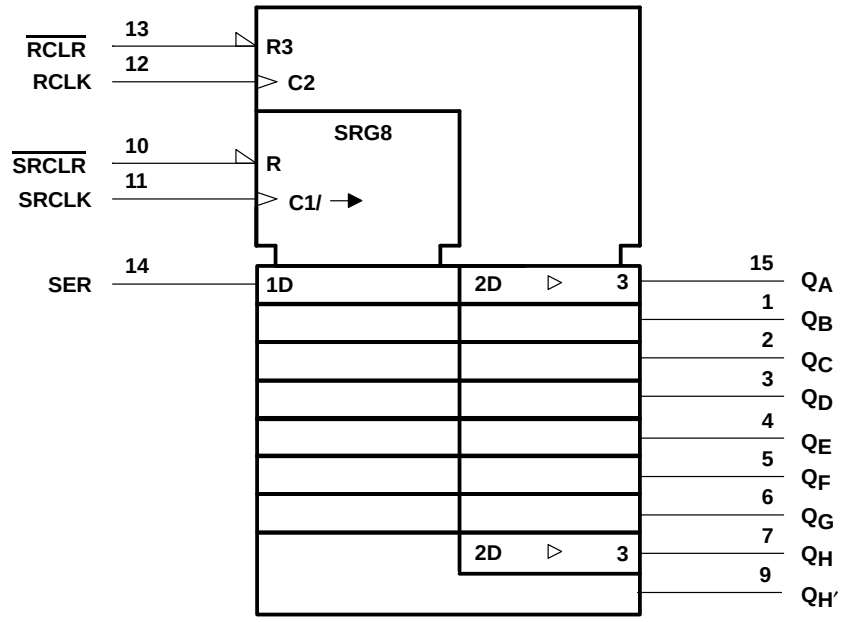
The ’HC594 contain an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. Separate clocks and direct overriding clear ($\overline{RCLR}$, $\overline{SRCLR}$) inputs are provided on both the shift and storage registers. A serial ($Q_{H'}$) output is provided for cascading purposes.

Both the shift register (RCLK) and storage register (SRCLK) clocks are positive edge triggered. If both clocks are connected together, the shift register is always one count pulse ahead of the storage register.

The parallel (Q_A–Q_H) outputs have high-current capability. $Q_{H'}$ is a standard output.

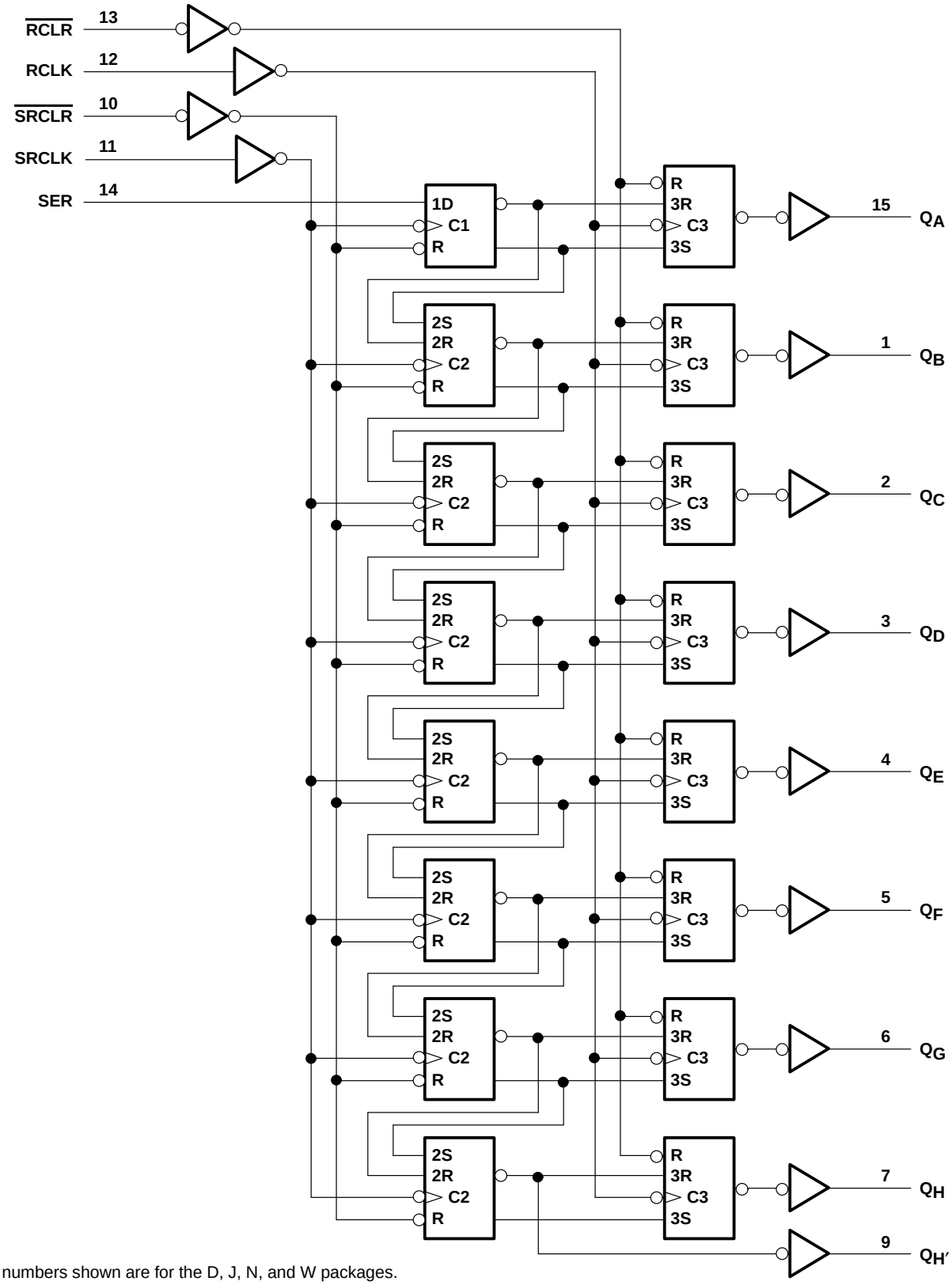
The SN54HC594 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC594 is characterized for operation from –40°C to 85°C.

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, J, N, and W packages.

logic diagram (positive logic)



Pin numbers shown are for the D, J, N, and W packages.

absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V_{CC} . . . . . –0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1) . . . . . ±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1) . . . . . ±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC}) . . . . . ±35 mA
Continuous current through V_{CC} or GND . . . . . ±70 mA
Package thermal impedance, θ_{JA} (see Note 2): D package . . . . . 113°C/W
N package . . . . . 78°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SN54HC594			SN74HC594			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		2	5	6	2	5	6	V
V_{IH}	High-level input voltage	V_{CC} = 2 V	1.5			1.5			V
		V_{CC} = 4.5 V	3.15			3.15			
		V_{CC} = 6 V	4.2			4.2			
V_{IL}	Low-level input voltage	V_{CC} = 2 V	0		0.5	0		0.5	V
		V_{CC} = 4.5 V	0		1.35	0		1.35	
		V_{CC} = 6 V	0		1.8	0		1.8	
V_I	Input voltage		0		V_{CC}	0		V_{CC}	V
V_O	Output voltage		0		V_{CC}	0		V_{CC}	V
t_t	Input transition (rise and fall) time	V_{CC} = 2 V	0		1000	0		1000	ns
		V_{CC} = 4.5 V	0		500	0		500	
		V_{CC} = 6 V	0		400	0		400	
T_A	Operating free-air temperature		–55		125	–40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V_{CC}	T_A = 25°C			SN54HC594		SN74HC594		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V_{OH}	V_I = V_{IH} or V_{IL}	I_{OH} = –20 μA	2 V	1.9	1.998		1.9		1.9		V
			4.5 V	4.4	4.499		4.4		4.4		
			6 V	5.9	5.999		5.9		5.9		
		$Q_{H'}$, I_{OH} = –4 mA	4.5 V	3.98	4.3		3.7		3.84		
		Q_A–Q_H, I_{OH} = –6 mA		3.98	4.3		3.7		3.84		
		$Q_{H'}$, I_{OH} = –5.2 mA	6 V	5.48	5.8		5.2		5.34		
		Q_A–Q_H, I_{OH} = –7.8 mA		5.48	5.8		5.2		5.34		
V_{OL}	V_I = V_{IH} or V_{IL}	I_{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	V
			4.5 V		0.001	0.1		0.1		0.1	
			6 V		0.001	0.1		0.1		0.1	
		$Q_{H'}$, I_{OL} = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		Q_A–Q_H, I_{OL} = 6 mA			0.17	0.26		0.4		0.33	
		$Q_{H'}$, I_{OL} = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
		Q_A–Q_H, I_{OL} = 7.8 mA			0.15	0.26		0.4		0.33	
I_I	V_I = V_{CC} or 0		6 V			±0.1	±100		±1000		nA
I_{OZ}	V_O = V_{CC} or 0		6 V			±0.01	±0.5		±10		±5	μA
I_{CC}	V_I = V_{CC} or 0,	I_O = 0	6 V			8		160		80	μA
C_i			2 V to 6 V		3	10		10		10	pF

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			V_{CC}	T_A = 25°C		SN54HC594		SN74HC594		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	
f_{clock}	Clock frequency		2 V	0	5	0	3.3	0	4	MHz
			4.5 V	0	25	0	17	0	20	
			6 V	0	29	0	20	0	24	
t_w	Pulse duration	SRCLK or RCLK high or low	2 V	100		150		125		ns
			4.5 V	20		30		25		
			6 V	17		25		21		
		$\overline{\text{SRCLR}}$ or $\overline{\text{RCLR}}$ low	2 V	100		150		125		
			4.5 V	20		30		25		
			6 V	17		25		21		
t_{su}	Setup time	SER before SRCLK↑	2 V	90		135		110		ns
			4.5 V	18		27		22		
			6 V	15		23		19		
		SRCLK↑ before RCLK↑†	2 V	90		135		110		
			4.5 V	18		27		22		
			6 V	15		23		19		
		$\overline{\text{SRCLR}}$ low before RCLK↑	2 V	50		75		63		
			4.5 V	10		15		13		
			6 V	9		13		11		
		$\overline{\text{SRCLR}}$ high (inactive) before SRCLK↑	2 V	20		20		20		
			4.5 V	10		10		10		
			6 V	10		10		10		
		$\overline{\text{RCLR}}$ high (inactive) before SRCLK↑	2 V	5		5		5		
			4.5 V	5		5		5		
			6 V	5		5		5		
t_h	Hold time, SER after SRCLK↑		2 V	5		5		5		ns
			4.5 V	5		5		5		
			6 V	5		5		5		

† This setup time ensures the output register sees stable data from the shift-register outputs. The clocks may be tied together, in which case the output register is one clock pulse behind the shift register.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC}	T_A = 25°C			SN54HC594		SN74HC594		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f_{max}			2 V	5	8		3.3		4		MHz
			4.5 V	25	35		17		20		
			6 V	29	40		20		24		
t_{pd}	SRCLK	$Q_{H'}$	2 V		50	150		225		185	ns
			4.5 V		20	30		45		37	
			6 V		15	25		38		31	
	RCLK	Q_A–Q_H	2 V		50	150		225		185	
			4.5 V		20	30		45		37	
			6 V		15	25		38		31	
t_{PHL}	$\overline{SRCLR}$	$Q_{H'}$	2 V		50	150		225		185	ns
			4.5 V		20	30		45		37	
			6 V		15	25		38		31	
	$\overline{RCLR}$	Q_A–Q_H	2 V		50	125		185		155	
			4.5 V		20	25		37		31	
			6 V		15	21		31		26	
t_t		$Q_{H'}$	2 V		38	75		110		95	ns
			4.5 V		8	15		22		19	
			6 V		6	13		19		16	
		Q_A–Q_H	2 V		38	60		90		75	
			4.5 V		8	12		18		15	
			6 V		6	10		15		13	

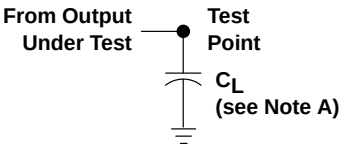
switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC}	T_A = 25°C			SN54HC594		SN74HC594		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{pd}	RCLK	Q_A–Q_H	2 V		90	200		300		250	ns
			4.5 V		23	40		60		50	
			6 V		19	34		51		43	
t_{PHL}	$\overline{RCLR}$	Q_A–Q_H	2 V		90	200		300		250	ns
			4.5 V		23	40		60		50	
			6 V		19	34		51		43	
t_t		Q_A–Q_H	2 V		45	210		315		265	ns
			4.5 V		17	42		63		53	
			6 V		13	36		53		45	

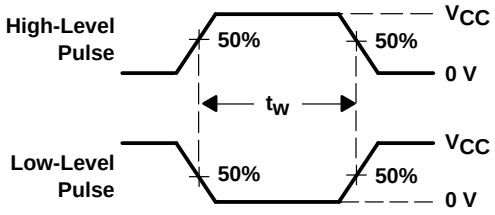
operating characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C_{pd}	Power dissipation capacitance	No load	395	pF

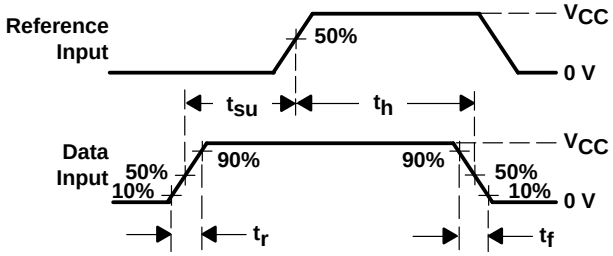
PARAMETER MEASUREMENT INFORMATION



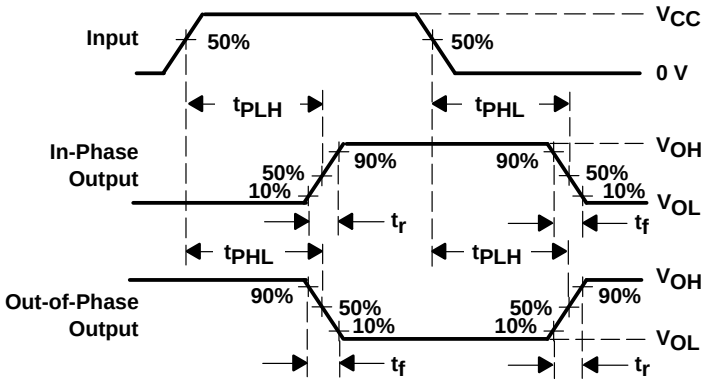
LOAD CIRCUIT



VOLTAGE WAVEFORMS
PULSE DURATIONS



VOLTAGE WAVEFORMS
SETUP AND HOLD AND INPUT RISE AND FALL TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

NOTES: A. C_L includes probe and test-fixture capacitance.
B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r = 6 ns, t_f = 6 ns.
C. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
D. The outputs are measured one at a time with one input transition per measurement.
E. t_{PLH} and t_{PHL} are the same as t_{pd}.

Figure 1. Load Circuit and Voltage Waveforms

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